

~~Subcl.~~ **IN THE CLAIMS:**

B1
1 1. (Twice Amended) A probe apparatus for testing a circuit chip, said probe
2 apparatus comprising a probe group having two or more probes within a guiding
3 boundary for independently conductively contacting a single terminal of said
4 circuit chip and allowing a test path resistance be measured without affecting said
5 circuit chip.

B2
1 2. (Amended) The probe apparatus of claim 1, further comprising an electronic circuit
2 capable of recognizing said test path resistance and correspondingly compensating a
3 voltage drop of an operational signal passing through at least one of said probes.